

## **New Test Beam Results of 3D and Pad Detectors Constructed with Poly-Crystalline CVD Diamond**

Vienna Conference on Instrumentation

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## Section 1

### Motivation

# Diamond as Detector Material

- innermost tracking layers  $\rightarrow$  highest radiation damage  $\mathcal{O}$  (GHz/cm<sup>2</sup>)
- current detectors is designed to survive  $\sim 12$  month in High-Luminosity LHC
- $\rightarrow$  **R/D for more radiation tolerant detector designs and/or materials**

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## Diamond as Detector Material:

- properties
  - ▶ radiation tolerant
  - ▶ isolating material
  - ▶ high charge carrier mobility
  - ▶ **smaller signal than in silicon with same thickness (large bandgap)**

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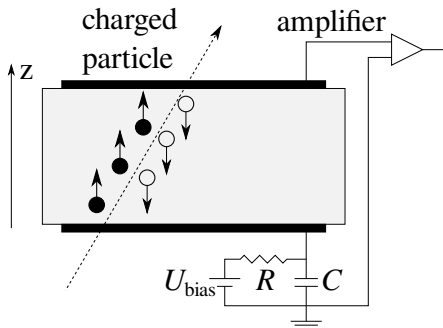
## Work of RD42:

- investigate signals and radiation tolerance in various detector designs:
  - ▶ **pad**  $\rightarrow$  full diamond as single cell readout
  - ▶ pixel  $\rightarrow$  diamond sensors on state-of-the-art pixel chips
  - ▶ **3D pixel**  $\rightarrow$  detector with design to reduce drift distance

## Section 2

### Introduction

# Diamond as Particle Detector



(a) Detector Schematics

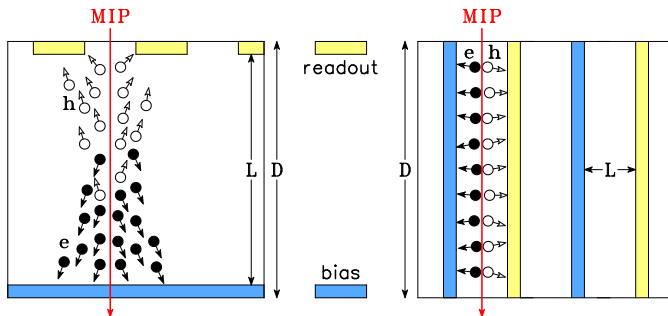


(b) 15 cm pCVD Diamond Wafer

- detectors operated as ionisation chambers
- poly-crystals produced in large wafers
- metallisation on both sides



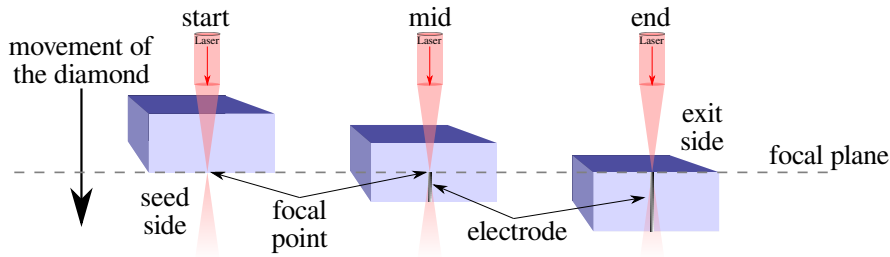
# Working Principle



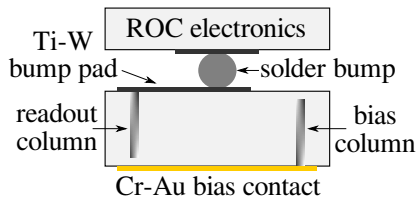
- after large radiation fluence all detectors become trap limited
- bias and readout electrode inside detector material
- same thickness  $D \rightarrow$  same amount of induced charge  $\rightarrow$  shorter drift distance  $L$
- **increase collected charge in detectors with limited mean free path**

# Laser drilling

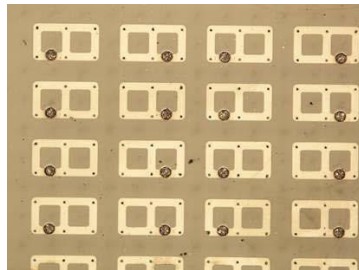
- “drilling” columns with  $\sim 15\text{ }\mu\text{m}$  gap to the surface using fs-laser (Oxford)
- convert diamond into resistive mixture of carbon phases (i.a. DLC, graphite, ...)
- usage of spatial light modulation (SLM) to correct for aberration
- initial column yield  $\sim 90\%$   $\rightarrow$  now  $\geq 99\%$
- initial column diameter  $6 \sim 10\text{ }\mu\text{m}$   $\rightarrow$  now  $2.6\text{ }\mu\text{m}$



# Bump Bonding



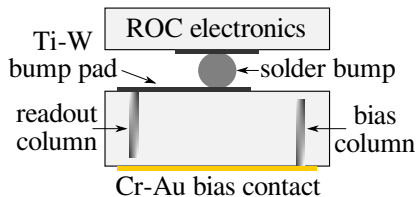
(a) Bump bond schematics



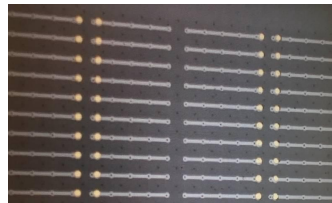
(b)  $3 \times 2$  bump pads

- connection to bias and readout with surface metallisation
- ganging of cells to match pixel pitch of readout-chip (ROC)
- small gap to the surface to avoid a break-through

# Bump Bonding



(a) Bump bond schematics



(b)  $1 \times 5$  bump pads

- connection to bias and readout with surface metallisation
- ganging of cells to match pixel pitch of readout-chip (ROC)
- small gap to the surface to avoid a break-through

# Progress in Diamond Detectors

## 3D Detectors:

- proved that 3D works in pCVD diamond
- scale up the number of columns per detector:  $\mathcal{O}(100) \rightarrow \mathcal{O}(1000)$  ( $\times 40$ )
- reducing the cell size:  $150\text{ }\mu\text{m} \times 150\text{ }\mu\text{m} \rightarrow 50\text{ }\mu\text{m} \times 50\text{ }\mu\text{m} \rightarrow 25\text{ }\mu\text{m} \times 25\text{ }\mu\text{m}$  (soon)
- reducing the diameter of the columns:  $6 \sim 10\text{ }\mu\text{m} \rightarrow 2.6\text{ }\mu\text{m} \rightarrow 1 \sim 2\text{ }\mu\text{m}$  (soon)
- $\rightarrow$  increasing column yield:  $\sim 90\% \rightarrow \geq 99\%$
- recently tested first irradiated  $50\text{ }\mu\text{m} \times 50\text{ }\mu\text{m}$  3D detector ( $3.5 \cdot 10^{15}\text{ n/cm}^2$ )

## 3D Pixel Detectors:

- visible improvements with each step reducing the cell size
- all worked as expected (to first order)

## Rate Studies in Pad Detectors:

- particle fluxes from  $1\text{ kHz/cm}^2$  up to  $20\text{ MHz/cm}^2$
- irradiations up to  $4 \cdot 10^{15}\text{ n/cm}^2$

## Section 3

### 3D Pixel Detectors

# 1 × 5 Ganging

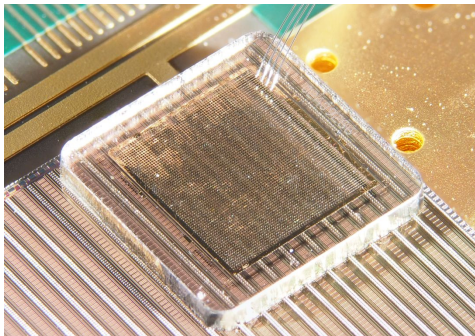
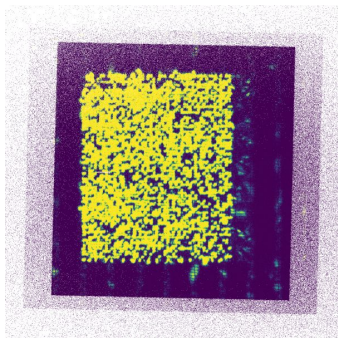


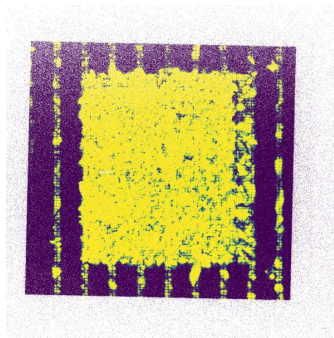
Figure: Final Detector

- readout chip (ROC): ATLAS FEI4
- Size: 5 mm × 5 mm
- active area 3 mm × 3 mm
- tin-silver bump bonding at IFAE (Barcelona)

# Efficiencies



(a) High threshold



(b) Low threshold

- efficiencies



# Time over Threshold

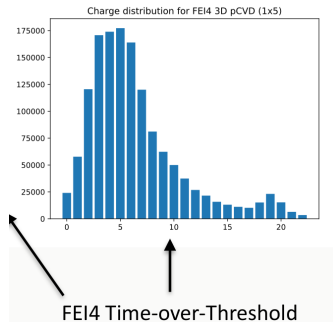


Figure: Time over Threshold

● tot

## 2 × 3 Ganging

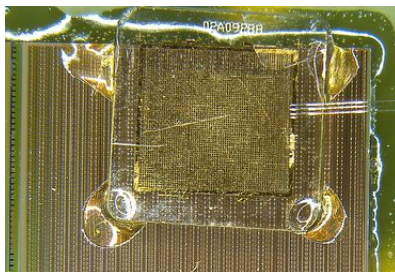
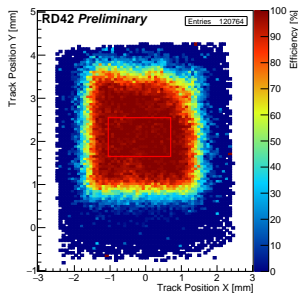


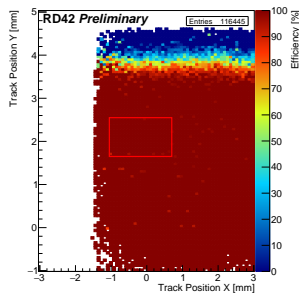
Figure: Final Detector

- readout chip (ROC): CMS PSI46digv2.1repspin
- Size: 5 mm × 5 mm
- active area 3.5 mm × 3.5 mm
- indium bump-bonding (Princeton)

# Efficiencies - First PSI Beam Test



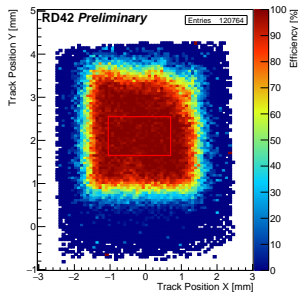
(a) Efficiency Map Diamond



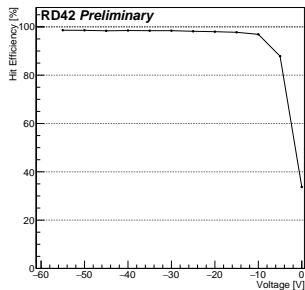
(b) Efficiency Map Silicon

- top right corner of the diamond badly bump bonded
- efficiency in red fiducial area: Diamond: 99.1 %, Silicon: 99.9 %

# Efficiencies - First PSI Beam Test



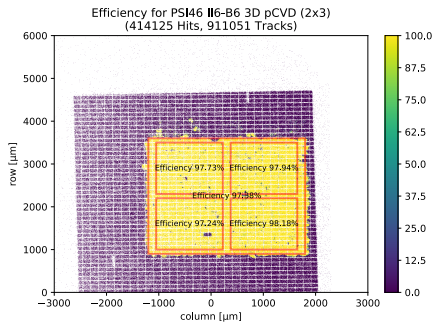
(a) Efficiency Map



(b) Efficiency vs. voltage

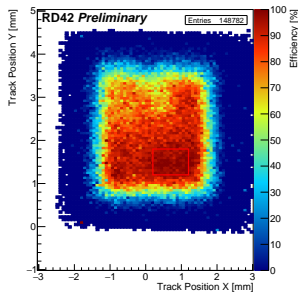
- top right corner of the diamond badly bump bonded
- effective efficiency in red fiducial area: 99.2 %
- already fully efficient at 20 V
- ROC malfunctioned after this beam test

# Efficiencies - CERN Beam Test

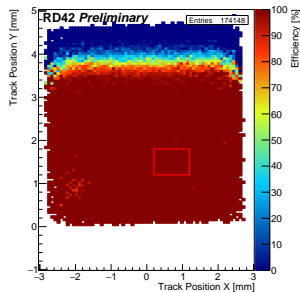


- high resolution measurement at CERN
- sensor twice re-bump-bonded with the same indium (no reprocessing)
- reduced efficiency

## Efficiencies - Second PSI Beam Test



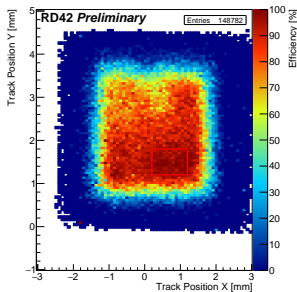
(a) Efficiency Map Diamond



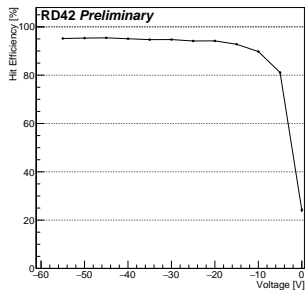
(b) Efficiency Map Silicon

- sensor twice re-bump-bonded with the same indium (no reprocessing)
- efficiency in red fiducial area: Diamond: 97.3 %, Silicon: 100.0 %

## Efficiencies - Second PSI Beam Test



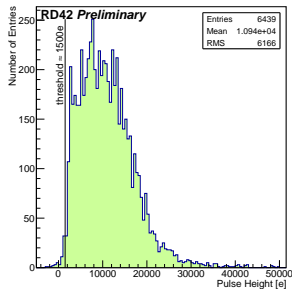
(a) Efficiency Map



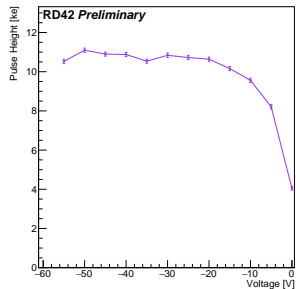
(b) Efficiency vs. voltage

- sensor twice re-bump-bonded with the same indium (no reprocessing)
- effective efficiency in red fiducial area: 97.3 %
- already fully efficient at 20 V
- only very small area working well → many bump bond problems

# Pulse Height - Second Beam Test



(a) Signal Distribution



(b) Pulse height vs. voltage

- wrong pulse height calibration in first beam test
- full charge collection also at 20 V
- mean pulse height lower than expected: 11 000 e
- probably connected to bad bump bonding



## Section 4

### Pad Detectors (Rate Studies)

# Leakage Currents

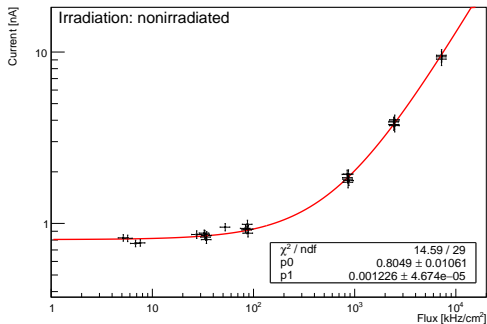
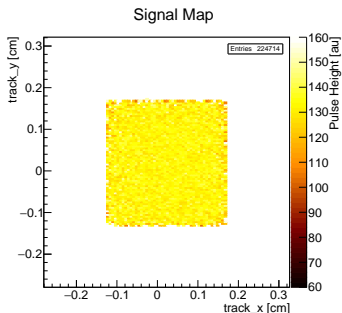


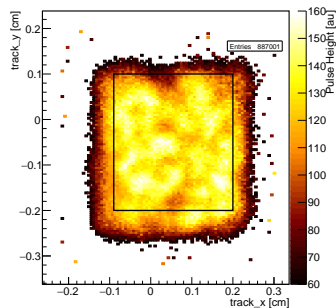
Figure: Leakage Current of a non-irradiated pCVD diamond

- leakage current of most of the diamonds linear in flux
- very low base leakage current (no beam) of  $\mathcal{O}(1 \text{ nA})$

# Signal Maps



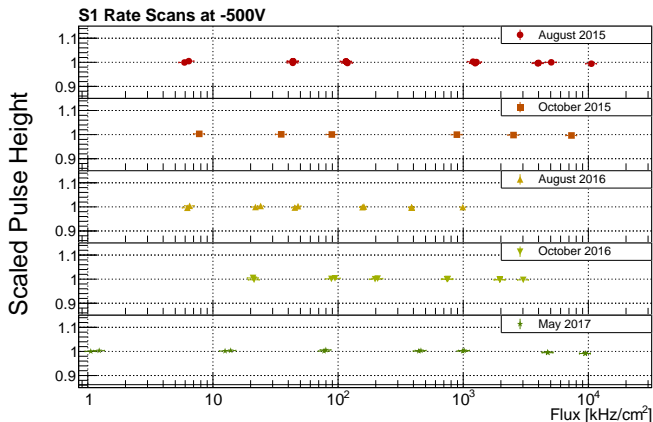
(a) scCVD (6 dB attenuation)



(b) pCVD

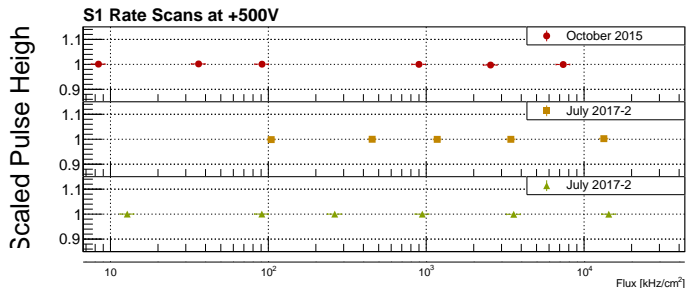
- uniform signal distribution in scCVD
- region dependent signal in pCVD

## Non-Irradiated scCVD



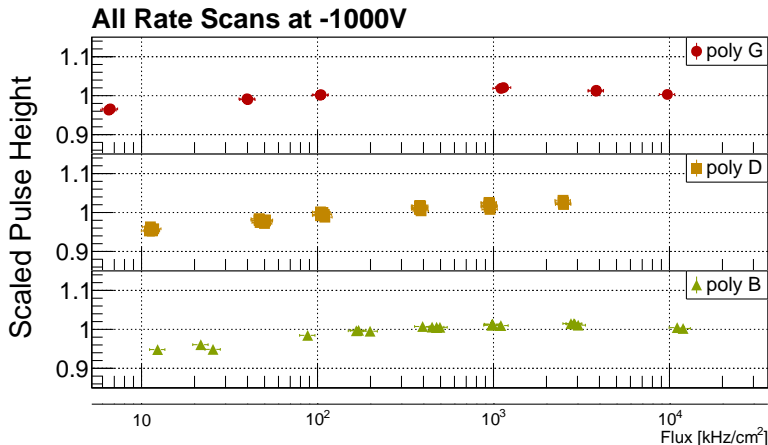
- rate scaled to the mean
- scCVD diamond shows now rate dependence within the measurement precision
- noise stays constant

## Non-Irradiated scCVD



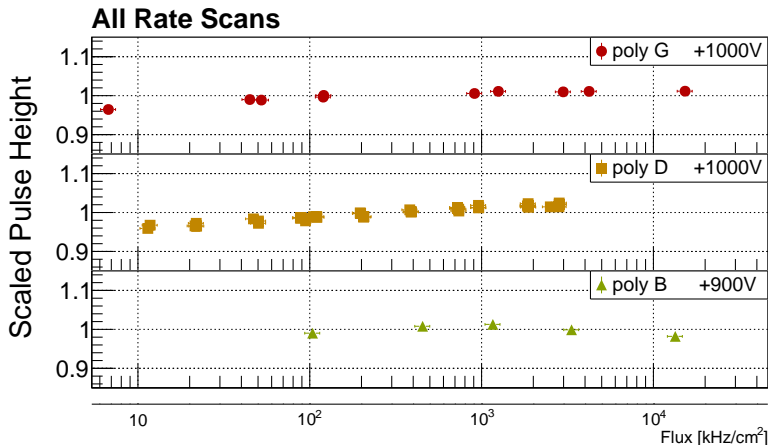
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## Non-Irradiated pCVD



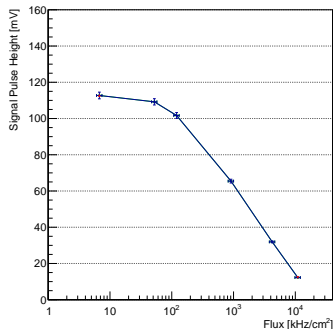
- rate scaled to the mean
- most non-irradiated pCVD diamonds have slight rate dependence (<5 %)
- behaviour very similar for both positive and negative bias voltage

## Non-Irradiated pCVD

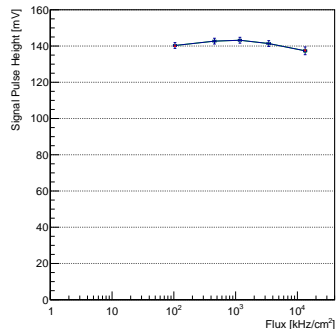


- rate scaled to the mean
- most non-irradiated pCVD diamonds have slight rate dependence ( $<5\%$ )
- behaviour very similar for both positive and negative bias voltage

# A Special Case



(a) First measurement

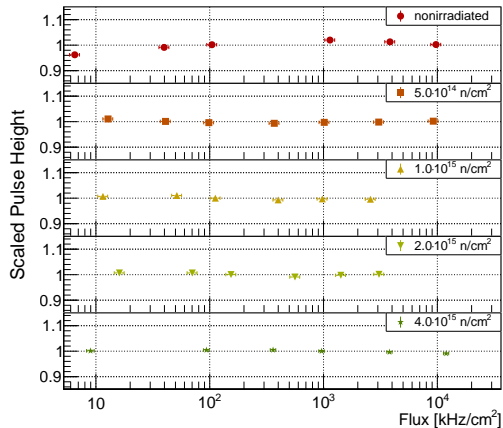


(b) After reprocessing

- very large rate dependence at the first measurement ( $>90\%$ )
- after reprocessing and surface cleaning with RIE very stable behaviour ( $\sim 2\%$ )
- feasible to “fix” bad diamonds



# Rate Studies in Irradiated pCVD



- rate scaled to the mean
- pulse height very stable after irradiation
- noise stays the same

## Section 5

### Conclusion

# Conclusion

- strongly improved fabrication of 3D diamonds
  - ▶ 40x more cells
  - ▶ smaller cell size
  - ▶ smaller columns
- 3D Detectors work well in pCVD diamond
  - ▶ 99.2 % efficiency
  - ▶ nearly full charge collection
- possible to repair pCVD diamonds with surface issues
- rate tests of irradiated pCVD diamonds up to  $4 \cdot 10^{15} \text{ n/cm}^2$
- irradiated pCVD diamond does not show rate dependence to  $\mathcal{O}(2\%)$

## Section 6

### Outlook

# Outlook

- results of  $3.5 \cdot 10^{15} \text{ n/cm}^2$  irradiated  $50 \mu\text{m} \times 50 \mu\text{m}$  detectors
- continue irradiation up to  $1 \cdot 10^{16} \text{ n/cm}^2$
- test both  $50 \mu\text{m} \times 50 \mu\text{m}$  and  $25 \mu\text{m} \times 25 \mu\text{m}$  pixel detectors
- reduce cell diameter to  $1 \sim 2 \mu\text{m}$
- build pixel device on newest RD53 chip ( $50 \mu\text{m} \times 50 \mu\text{m}$  pixel pitch)
- continue scale up by 10x

# DEL FIN

